

Description

The 6N137 is consists of an infrared emitting diode optically coupled to a high speed integrated photo detector logic gate with a strobable output. It is packaged in a 8-pin

DIP package and available in wide-lead spacing and SMD options.

Features

- High speed 10Mbit/s
- 10kV/µs min. common mode transient immunity (HT2611)
- Guaranteed performance from -40 to 85°C
- Logic gate output
- High isolation voltage between input and output (Viso=5000 V rms)
- Pb free and RoHS compliant.

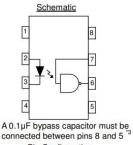
Applications

- Ground loop elimination
- LSTTL to TTL, LSTTL or 5 volt CMOS
- Line receiver, data transmission
- Data multiplexing
- Switching power supplies
- Pulse transformer replacement
- Computer peripheral interface
- High speed logic ground isolation

Truth Table (Positive Logic)

Input	Enable	Output		
Н	Н	L		
L	Н	Н		
Н	L	Н		
L	L	Н		
Н	NC	L		
L	NC	Н		





- Pin Configuration 1, No Connection
- 2, Anode
- 3, Cathode 4. No Connection
- 6, Vout
- 7, V_E 8, V_CC



Maximum Ratings(Ta=25°C)

Parameter		Symbol	Values	Unit
	Forward Current	I _F	50	mA
Enable input voltage Not exceed VCC by more than 500mV		VE	5.5	V
	Reverse voltage	V_{R}	5	V
	Power dissipation	P_D	100	mW
	Power dissipation	PC	85	mW
Output current		V_{ECO}	50	mA
Output Voltage		VO	7.0	V
Supply voltage		VCC	7.0	V
Output Power Dissipation		Po	100	mW
Isolation voltage ⁽¹⁾		V _{ISO}	5000	V rms
Operating temperature		T _{OPR}	-40 ~ +85	°C
Storage temperature		T _{STG}	-55 ~ +125	°C
Soldering temperature (2)		T _{SOL}	260	°C

Notes:

Electronic Optical Characteristics (TA = -40 to 85°C unless specified otherwise)

	Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditon
	Forward Voltage	V_{F}	•	1.4	1.8	V	I _F =10mA
	Reverse voltage	V_R	5.0	-	-	V	I _R =10µA
Input	Temperature coefficient of forward voltage	ΔVF/ΔΤΑ	-	-1.8	-	mV/°C	IF =10mA
	Input capacitance	Cin	-	60	-	pF	V⊧=0, f=1MHz
Output	High level supply current	Іссн	-	7	10	mA	I _F =0mA, V _E =0.5V, V _{CC} =5.5V
	Low level supply current	Iccl	-	9	13	mA	I⊧=10mA, Vcc=5.5V
	High level enable current ⁽³⁾	ІЕН	1	-0.6	-1.6	mA	V _E =2.0 V, V _{CC} =5.5V
	Low level enable current ⁽³⁾	ĪEL	1	-0.8	-1.6	mA	V _E =0.5 V, V _{CC} =5.5V
	High level enable voltage ⁽³⁾	VEH	2.0	-	-	V	I _F =10mA, Vcc=5.5V
	Low level enable voltage ⁽³⁾⁽⁴⁾	VEL	-	-	0.8	V	I⊧=10mA, Vcc=5.5V

^{(1).} AC for 1 minute, R.H.= $40 \sim 60\%$ R.H. In this test, pins 1, 2, 3 & 4 are shorted together, and pins 5, 6, 7 & 8 are shorted together.

^{(2).}For 10 seconds



Transfer Characteristics (Ta=-40 to 85°C unless specified otherwise)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditon
HIGH Level Output Current	Іон	-	2.1	100	uA	Vcc=5.5V, Vo=5.5V, I⊧=250µA, V _E =2.0V
LOW Level Output Current	Vol	-	0.35	0.6	V	Vcc = 5.5V, IF=5mA, VE=2.0V, IcL=13mA
Input Threshold Current	lғт	-	2.5	5	mA	Vcc= 5.5V, Vo=0.6V, VE=2.0V, IoL=13mA

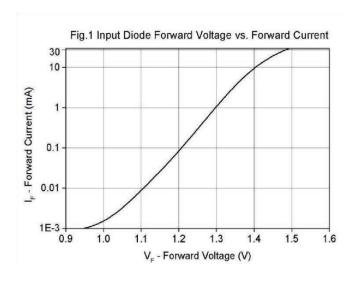
Switching Characteristics

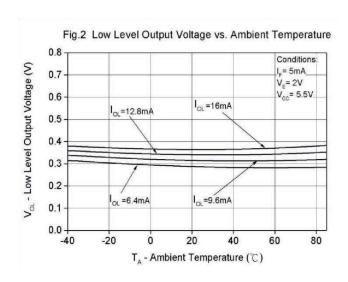
(Ta=-40 to 85°C, VCC=5V, IF=7.5mA unless specified otherwise)

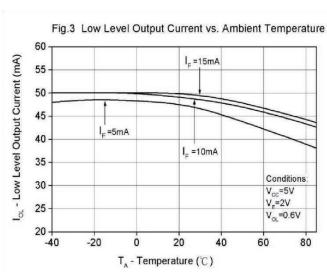
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Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditon
Propagation delay time to output High level ⁽⁵⁾ (Fig.12)	Трнц	-	35	75	ns	C _L = 15pF, R _L =350Ω, T _A =25°C
Propagation delay time to output Low level ⁽⁶⁾ (Fig.12)	Трін	-	40	75	ns	C _L = 15pF, R _L =350Ω, T _A =25°C
Pulse width distortion	Tphl – Tplh	-	5	35	ns	C _L = 15pF, R _L =350Ω
Output rise time ⁽⁷⁾ (Fig.12)	tr	-	40	-	ns	C _L = 15pF, R _L =350Ω
Output fall time ⁽⁸⁾ (Fig.12)	tf	-	10	-	ns	C∟ = 15pF, R∟=350Ω
Enable Propagation Delay Time to Output High Level ⁽⁹⁾ (Fig.13)	tегн	-	15	-	ns	IF = 7.5mA , VEH=3.5V, CL=15pF, RL=350Ω
Enable Propagation Delay Time to Output Low Level ⁽¹⁰⁾ (Fig.13)	tенL	-	15	-	ns	$\begin{array}{l} I_F = 7.5 \text{mA} , \\ V_{\text{EH}} = 3.5 \text{V}, \\ C_{\text{L}} = 15 \text{pF}, \\ R_{\text{L}} = 350 \Omega \end{array}$

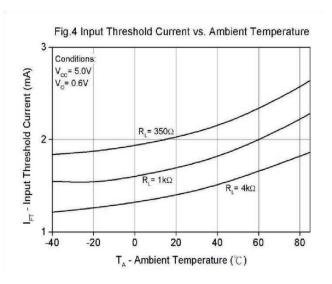


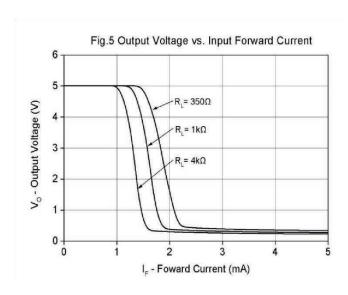
Typical Electro-Optical Characteristics Curves

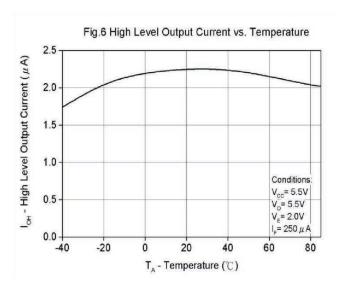




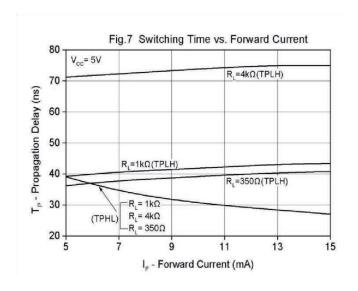


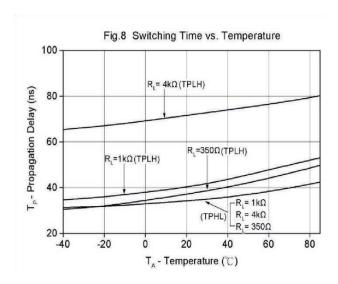


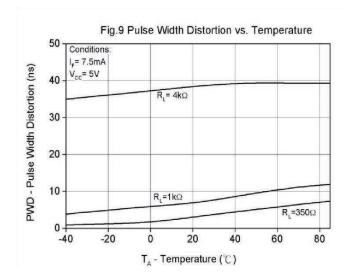


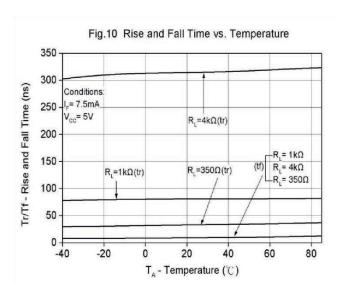


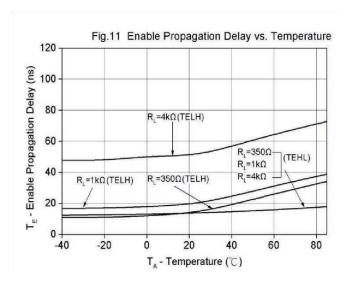












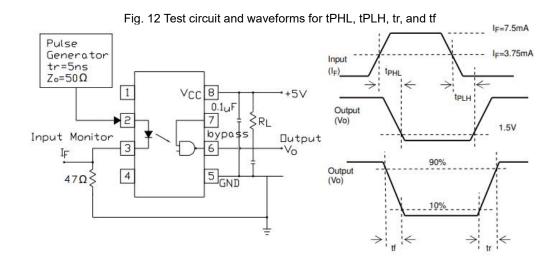
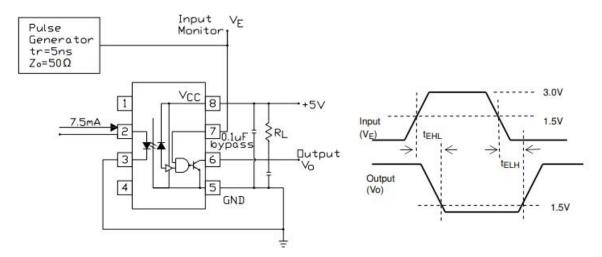


Fig. 13 Test circuit and waveform for tEHLand tELH



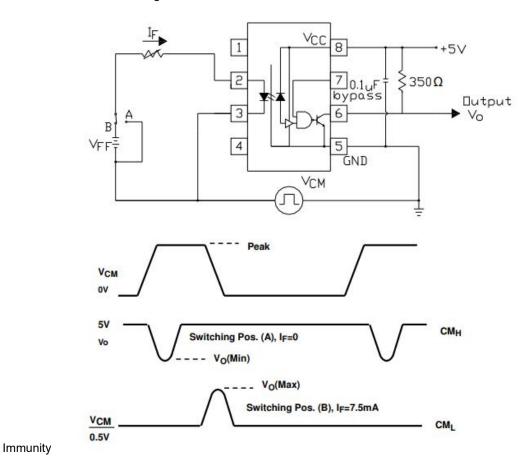


Fig. 14 Test circuit Common mode Transient

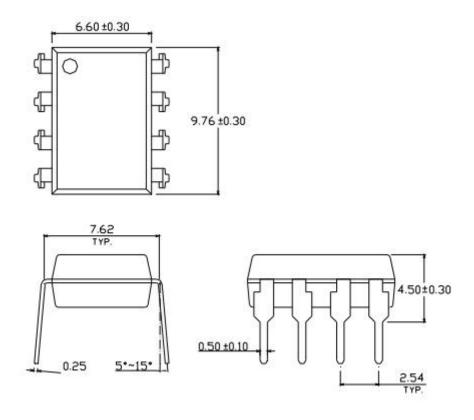
Note

- (3) The VCC supply must be bypassed by a 0.1µF capacitor or larger. This can be either a ceramic or solid tantalum capacitor with good high frequency characteristic and should be connected as close as possible to the package VCC and GND pins
- (4) Enable Input No pull up resistor required as the device has an internal pull up resistor.
- (5) tPLH– Propagation delay is measured from the 3.75mA level on the HIGH to LOW transition of the input current pulse to the 1.5 V level on the LOW to HIGH transition of the output voltage pulse.
- (6) tPHL– Propagation delay is measured from the 3.75mA level on the LOW to HIGH transition of the input current pulse to the 1.5 V level on the HIGH to LOW transition of the output voltage pulse.
- (7) tr– Rise time is measured from the 90% to the 10% levels on the LOW to HIGH transition of the output pulse.
- (8) tf- Fall time is measured from the 10% to the 90% levels on the HIGH to LOW transition of the output pulse.
- (9) tELH– Enable input propagation delay is measured from the 1.5V level on the HIGH to LOW transition of the input voltage pulse to the 1.5V level on the LOW to HIGH transition of the output voltage pulse.
- (10) tEHL– Enable input propagation delay is measured from the 1.5V level on the LOW to HIGH transition of the input voltage pulse to the 1.5V level on the HIGH to LOW transition of the output voltage pulse.
- (11) CMH– The maximum tolerable rate of rise of the common mode voltage to ensure the output will remain in the HIGH state (i.e., VOUT > 2.0V).
- (12) CML– The maximum tolerable rate of rise of the common mode voltage to ensure the output will remain in the LOW output state (i.e., VOUT < 0.8V).



Outline Dimension

DIP-8



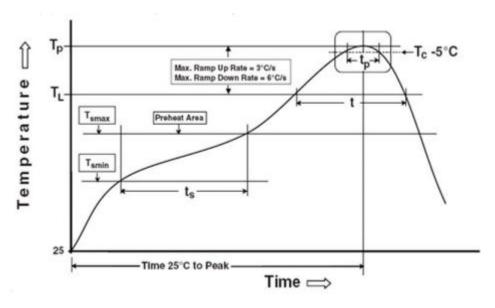


Temperature Profile Of Soldering

1. IR Reflow soldering

(IPC/JEDEC J-STD-020D compliant)

Profile item	Conditon			
Preheat Temperature min (Tsmin)	150 °C 200°C			
Temperature max (Tsmax) Time (Tsmin to Tsmax) (ts) Average ramp-up rate (Tsmax to Tp)	60-120 seconds 3 °C/ second max			
Other Liquidus Temperature (TL)	217 °C			
Time above Liquidus Temperature (tL) Peak Temperature (TP)	60-100 sec 260°C			
Time within 5 °C of Actual Peak Temperature: TP - 5°C Ramp- Down Rate from Peak Temperature Time 25°C to peak temperature Reflow times	30 s 6°C /second max. 8 minutes max. 3 times			



Notes:

One time soldering reflow is recommended within the condition of temperature and time profile shown below. Do not solder more than three times.



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